

RFD14N05L, RFD14N05LSM, RFP14N05L

14A, 50V, Avalanche Rated, Logic Level
N-Channel Enhancement-Mode Power MOSFETs

December 1995

Features

- 14A, 50V
- $r_{DS(ON)} = 0.100\Omega$
- *Temperature Compensating* PSPICE Model
- Can be Driven Directly from CMOS, NMOS, and TTL circuits
- Peak Current vs Pulse Width Curve
- UIS Rating Curve
- +175°C Operating Temperature

Description

The RFD14N05L, RFD14N05LSM, and RFP14N05L are N-channel power MOSFETs manufactured using the MegaFET process. This process, which uses feature sizes approaching those of LSI integrated circuits, gives optimum utilization of silicon, resulting in outstanding performance. They were designed for use in applications such as switching regulators, switching converters, motor drivers and relay drivers. This performance is accomplished through a special gate oxide design which provides full rated conductance at gate bias in the 3V - 5V range, thereby facilitating true on-off power control directly from logic level (5V) integrated circuits.

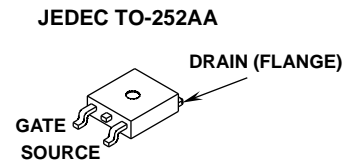
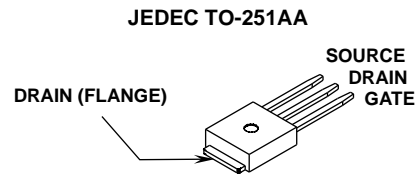
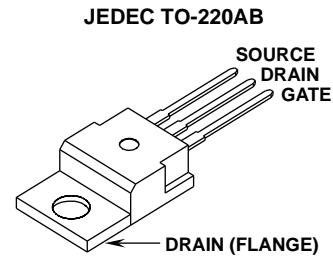
PACKAGE AVAILABILITY

PART NUMBER	PACKAGE	BRAND
RFD14N05L	TO-251AA	14N05L
RFD14N05LSM	TO-252AA	14N05L
RFP14N05L	TO-220AB	FP14N05L

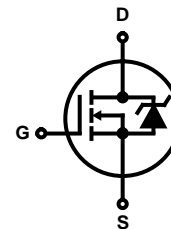
NOTE: When ordering, use the entire part number. Add the suffix 9A, to obtain the TO-252AA variant in tape and reel, i.e. RFD14N05LSM9A.

Formerly developmental type TA09870.

Packaging



Symbol



Absolute Maximum Ratings $T_C = +25^\circ\text{C}$

	RFD14N05L, RFD14N05LSM, RFP14N05L	UNITS
Drain-Source Voltage	V_{DSS} 50	V
Drain-Gate Voltage	V_{DGR} 50	V
Gate-Source Voltage	V_{GS} ± 10	V
Drain Current		
RMS Continuous	I_D 14	A
Pulsed Drain Current	I_{DM} Refer to Peak Current Curve	
Pulsed Avalanche Rating	E_{AS} Refer to UIS Curve	
Power Dissipation		
$T_C = +25^\circ\text{C}$	P_D 48	W
Derate above +25°C	0.32	W/°C
Operating and Storage Temperature	T_{STG}, T_J -55 to +175	°C
Soldering Temperature of Leads for 10s	T_L 260	°C

Specifications RFD14N05L, RFD14N05LSM, RFP14N05L

Electrical Specifications $T_C = +25^\circ\text{C}$, Unless Otherwise Specified

PARAMETERS	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS		
Drain-Source Breakdown Voltage	V_{DSS}	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	50	-	-	V		
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$	1	-	2	V		
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 50\text{V}$, $V_{GS} = 0\text{V}$	$T_C = +25^\circ\text{C}$	-	-	1	μA	
			$T_C = +150^\circ\text{C}$	-	-	50	μA	
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 10\text{V}$	-	-	100	nA		
On Resistance	$r_{DS(ON)}$	$I_D = 14\text{A}$, $V_{GS} = 5\text{V}$	-	-	0.100	Ω		
Turn-On Time	t_{ON}	$V_{DD} = 25\text{V}$, $I_D = 7\text{A}$, $R_L = 3.57\Omega$, $V_{GS} = 5\text{V}$, $R_{GS} = 0.6\Omega$	-	-	60	ns		
Turn-On Delay Time	$t_{D(ON)}$		-	13	-	ns		
Rise Time	t_R		-	24	-	ns		
Turn-Off Delay Time	$t_{D(OFF)}$		-	42	-	ns		
Fall Time	t_F		-	16	-	ns		
Turn-Off Time	t_{OFF}		-	-	100	ns		
Total Gate Charge	$Q_{G(TOT)}$		$V_{GS} = 0\text{V to } 10\text{V}$	$V_{DD} = 40\text{V}$, $I_D = 14\text{A}$, $R_L = 2.86\Omega$	-	-	40	nC
Gate Charge at 5V	$Q_{G(5)}$		$V_{GS} = 0\text{V to } 5\text{V}$		-	-	25	nC
Threshold Gate Charge	$Q_{G(TH)}$	$V_{GS} = 0\text{V to } 1\text{V}$	-		-	1.5	nC	
Input Capacitance	C_{ISS}	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	670	-	pF		
Output Capacitance	C_{OSS}		-	185	-	pF		
Reverse Transfer Capacitance	C_{RSS}		-	50	-	pF		
Thermal Resistance Junction-to-Case	$R_{\theta JC}$		-	-	3.125	$^\circ\text{C/W}$		
Thermal Resistance Junction-to-Ambient	$R_{\theta JA}$	TO-251 and TO-252	-	-	100	$^\circ\text{C/W}$		
		TO-220	-	-	80	$^\circ\text{C/W}$		

Source-Drain Diode Ratings and Specifications

PARAMETERS	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Forward Voltage	V_{SD}	$I_{SD} = 14\text{A}$	-	-	1.5	V
Reverse Recovery Time	t_{RR}	$I_{SD} = 14\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	125	ns

Typical Performance Curves

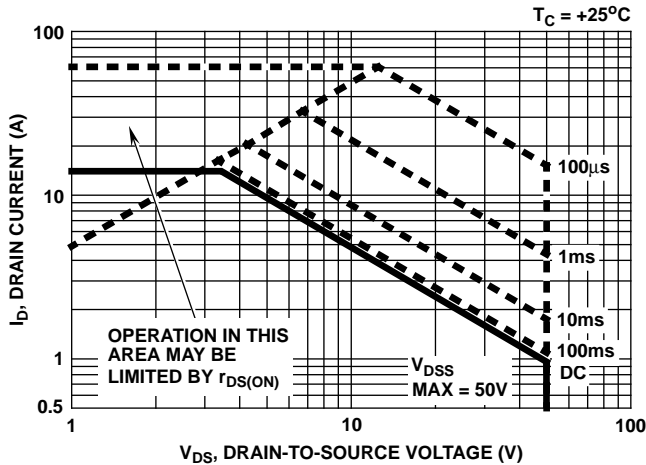


FIGURE 1. SAFE OPERATING AREA CURVE

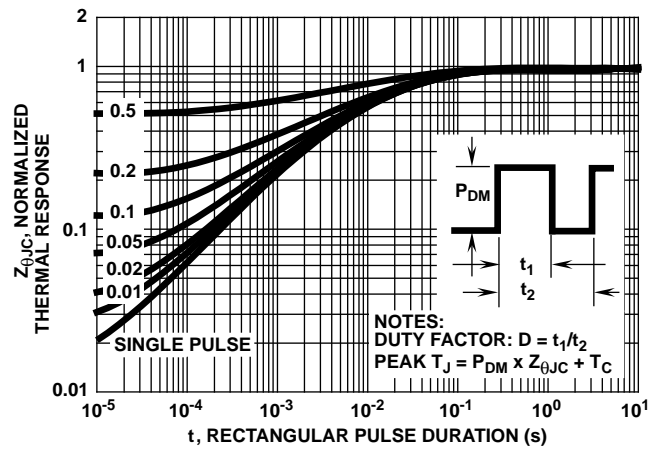


FIGURE 2. NORMALIZED MAXIMUM TRANSIENT THERMAL IMPEDANCE

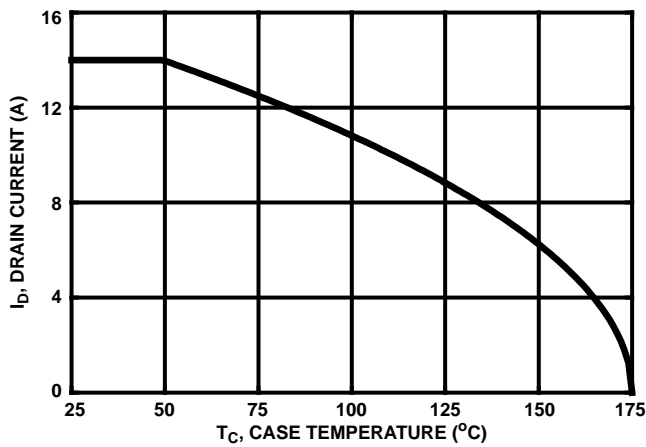


FIGURE 3. MAXIMUM CONTINUOUS DRAIN CURRENT vs TEMPERATURE

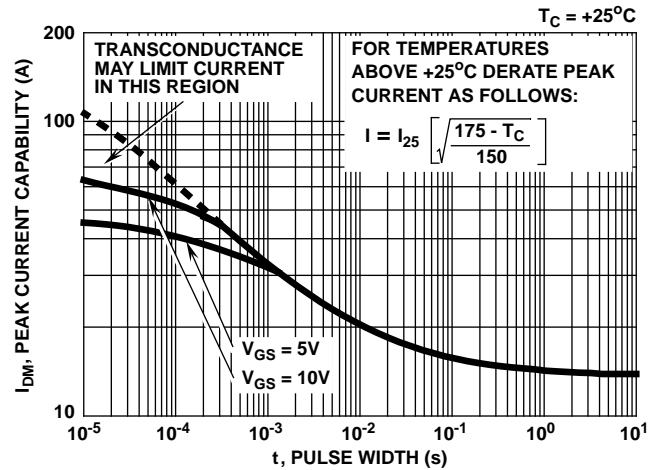


FIGURE 4. PEAK CURRENT CAPABILITY

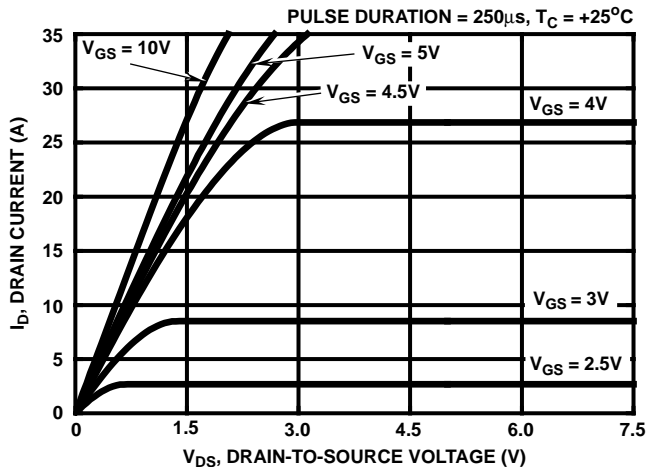


FIGURE 5. TYPICAL SATURATION CHARACTERISTICS

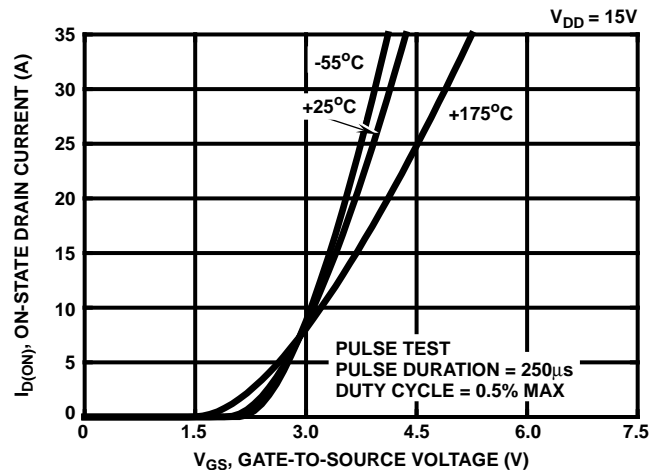


FIGURE 6. TYPICAL TRANSFER CHARACTERISTICS

Typical Performance Curves (Continued)

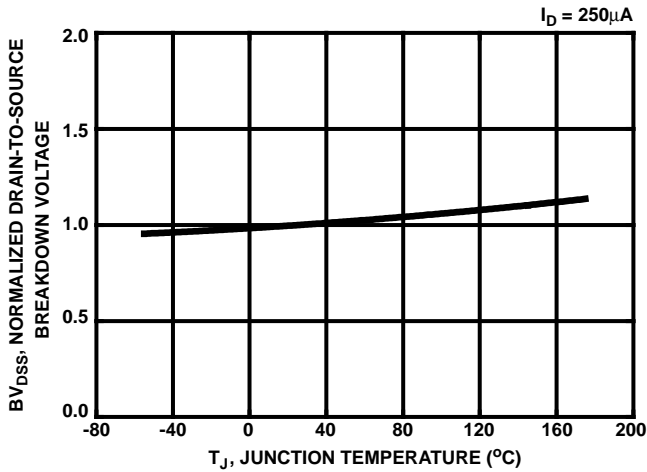


FIGURE 7. NORMALIZED DRAIN-SOURCE BREAKDOWN VOLTAGE vs JUNCTION TEMPERATURE

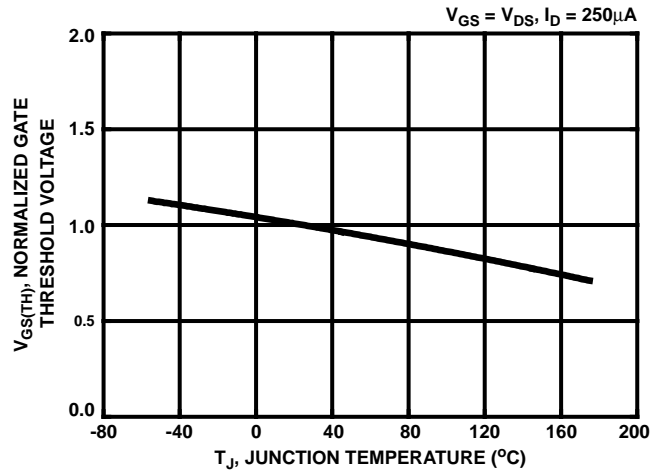


FIGURE 8. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE

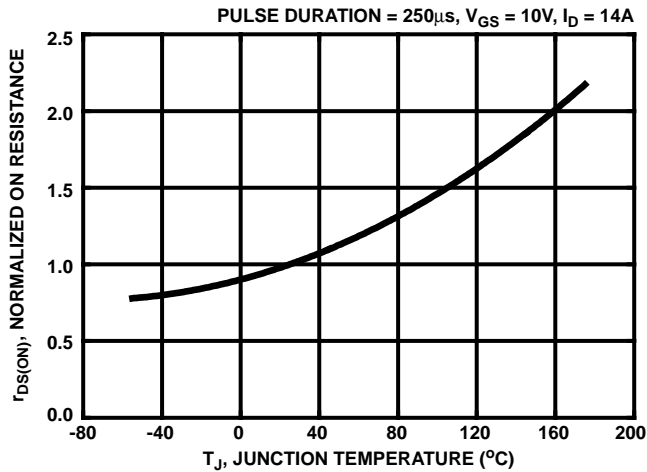


FIGURE 9. NORMALIZED $r_{DS(ON)}$ vs JUNCTION TEMPERATURE

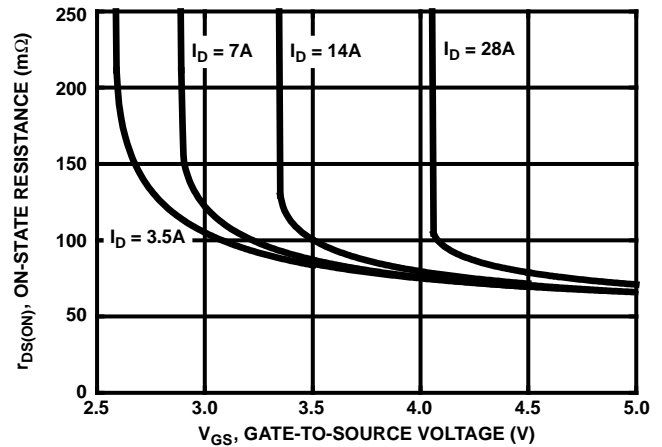


FIGURE 10. $r_{DS(ON)}$ FOR VARYING CONDITIONS OF GATE VOLTAGE AND DRAIN CURRENT

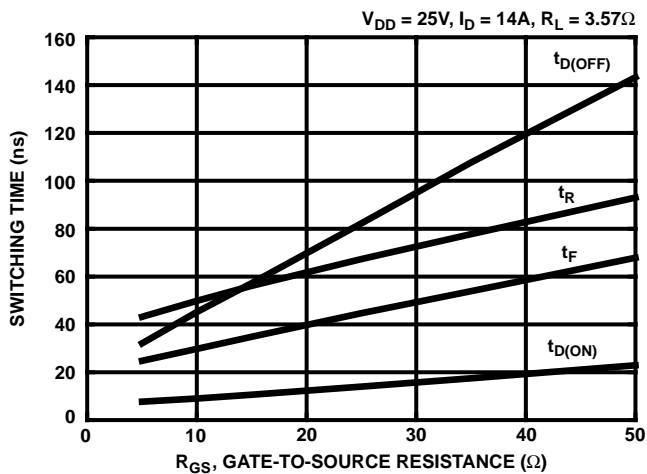


FIGURE 11. SWITCHING TIME AS A FUNCTION OF GATE RESISTANCE

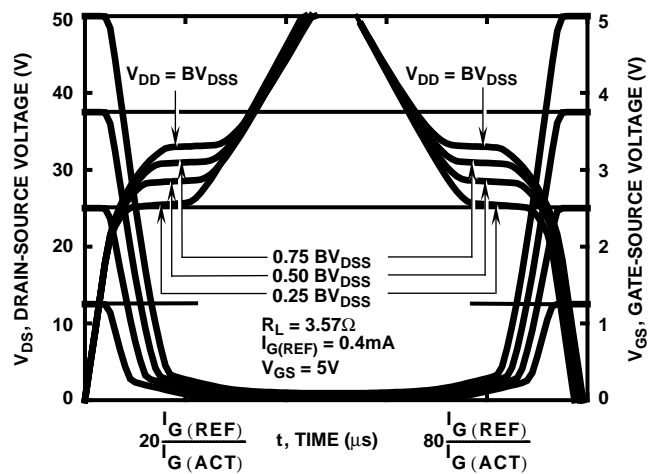


FIGURE 12. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT. REFER TO HARRIS APPLICATION NOTES AN7254 AND AN7260

Typical Performance Curves (Continued)

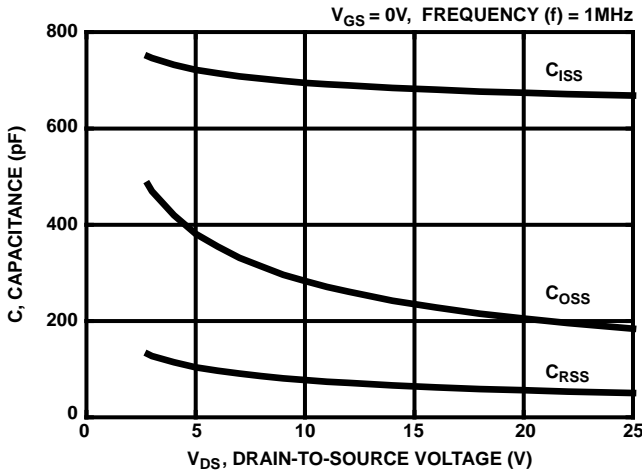


FIGURE 13. TYPICAL CAPACITANCE vs VOLTAGE

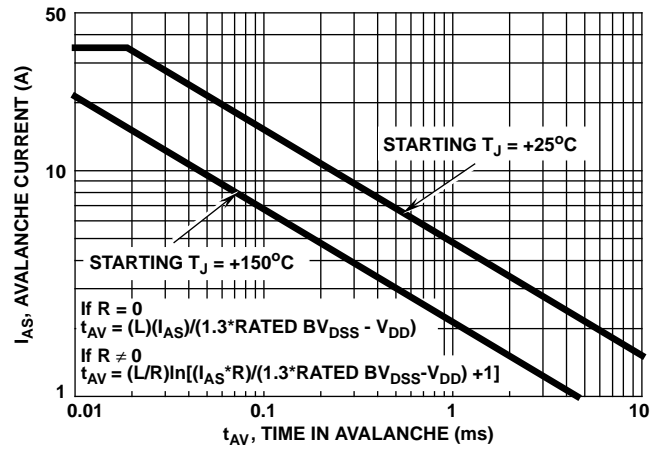


FIGURE 14. UNCLAMPED INDUCTIVE SWITCHING. REFER TO HARRIS APPLICATION NOTES AN9321 AND AN9322

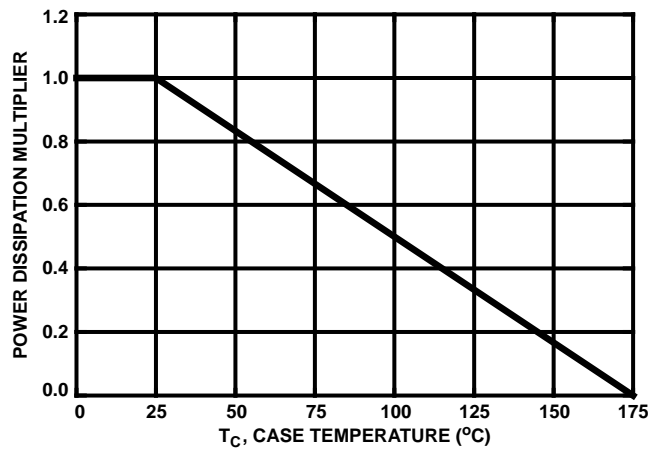


FIGURE 15. NORMALIZED POWER DISSIPATION vs TEMPERATURE DERATING CURVE

Test Circuits and Waveforms

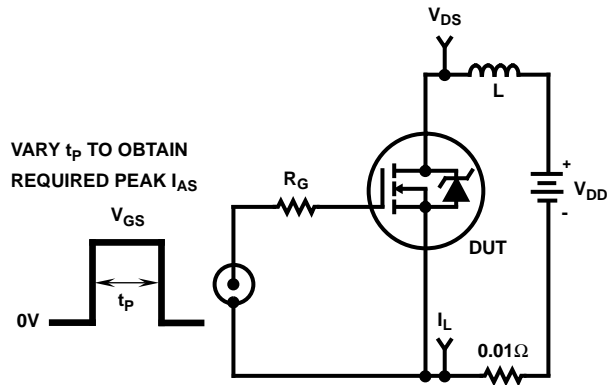


FIGURE 16. UNCLAMPED ENERGY TEST CIRCUIT

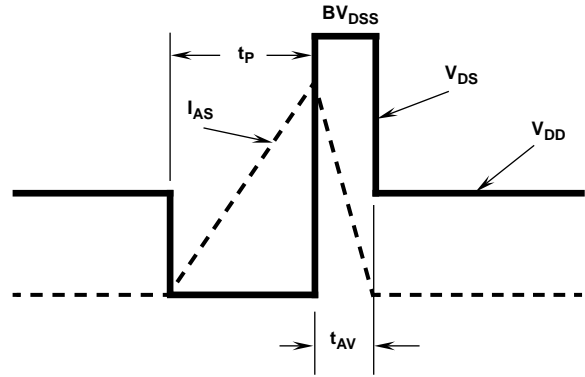


FIGURE 17. UNCLAMPED ENERGY WAVEFORMS

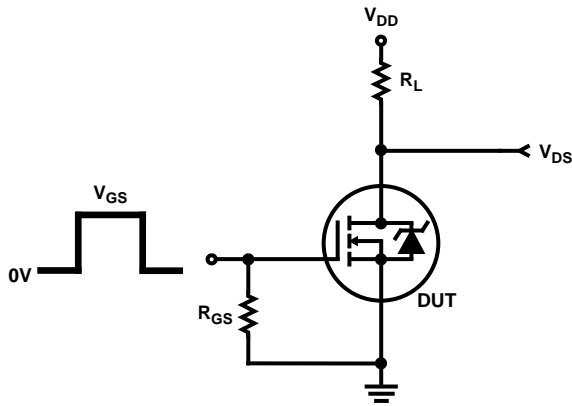


FIGURE 18. RESISTIVE SWITCHING TEST CIRCUIT

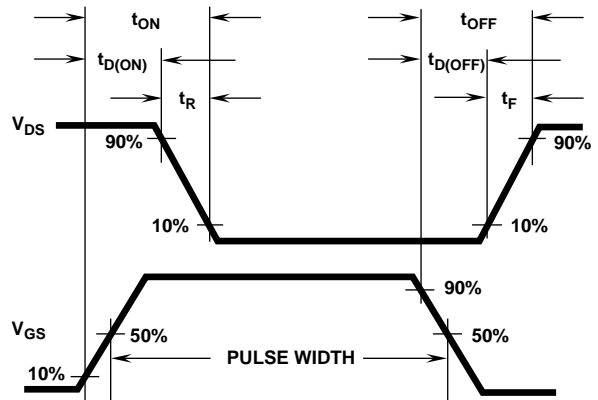


FIGURE 19. RESISTIVE SWITCHING WAVEFORMS

